

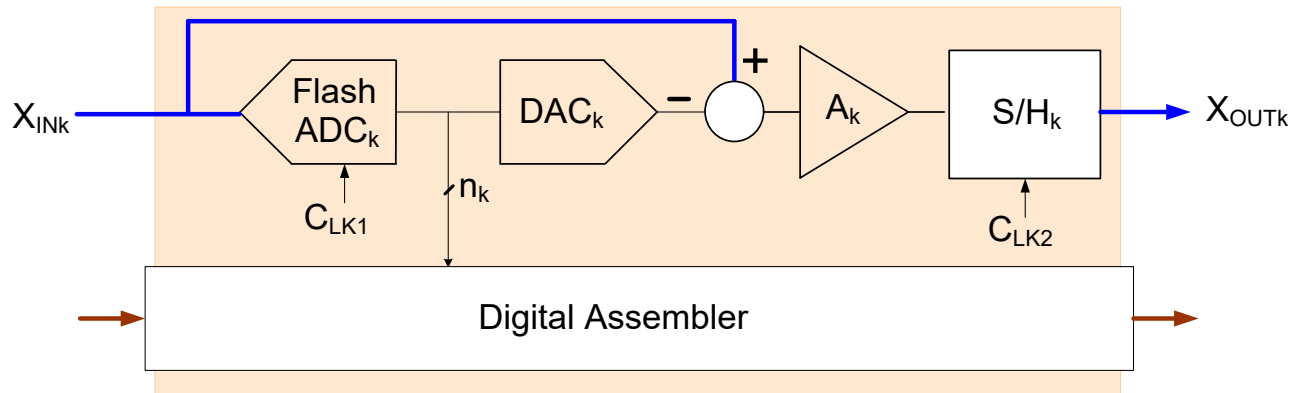
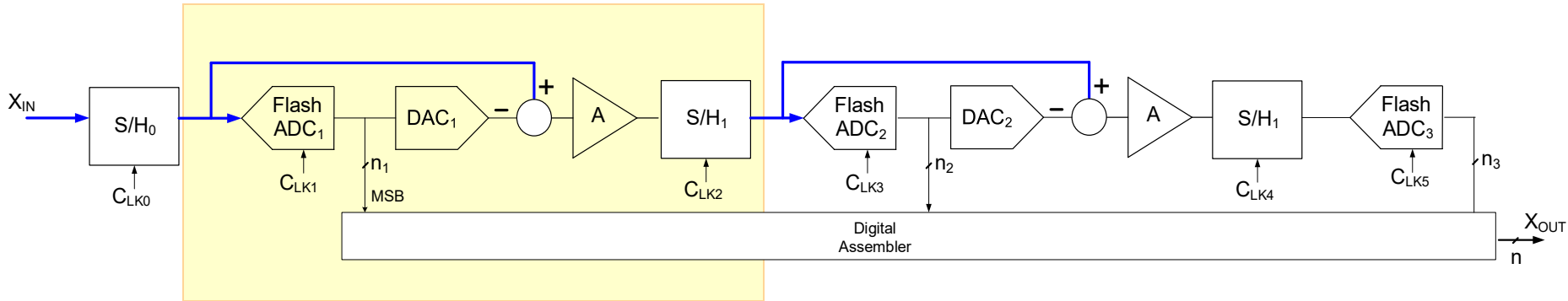
# EE 435

## Lecture 37

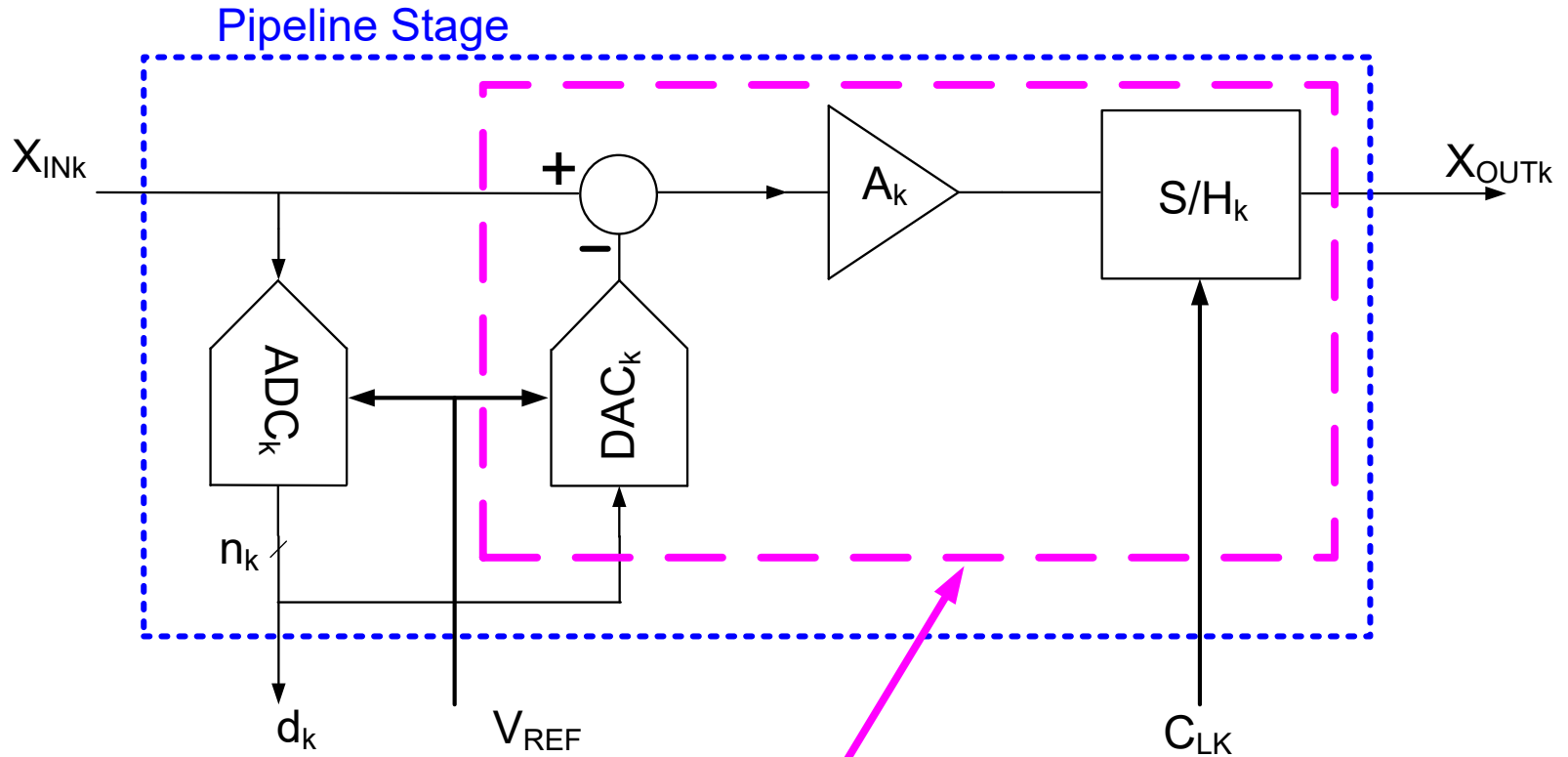
### ADC Design

Review from Last Lecture

# Three-Step Flash ADC with Interstage Gain

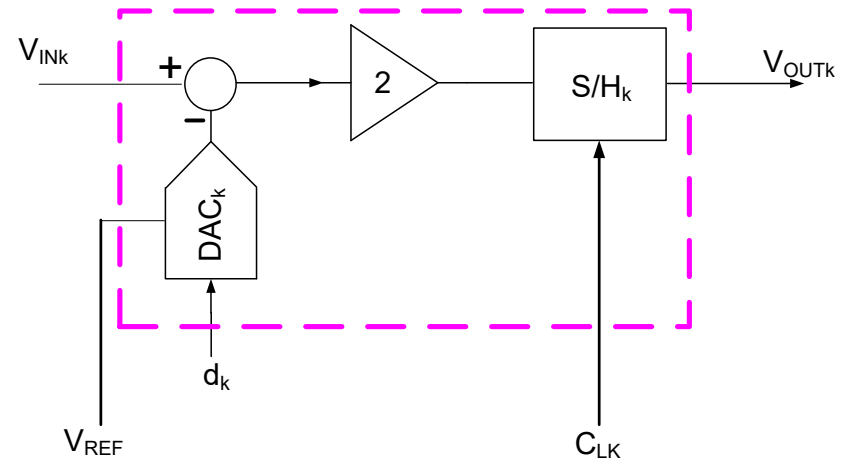
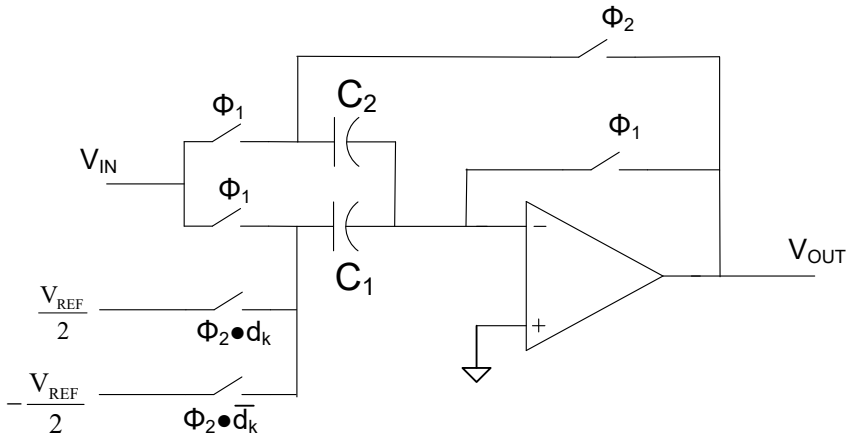


# Pipelined ADC Stage k



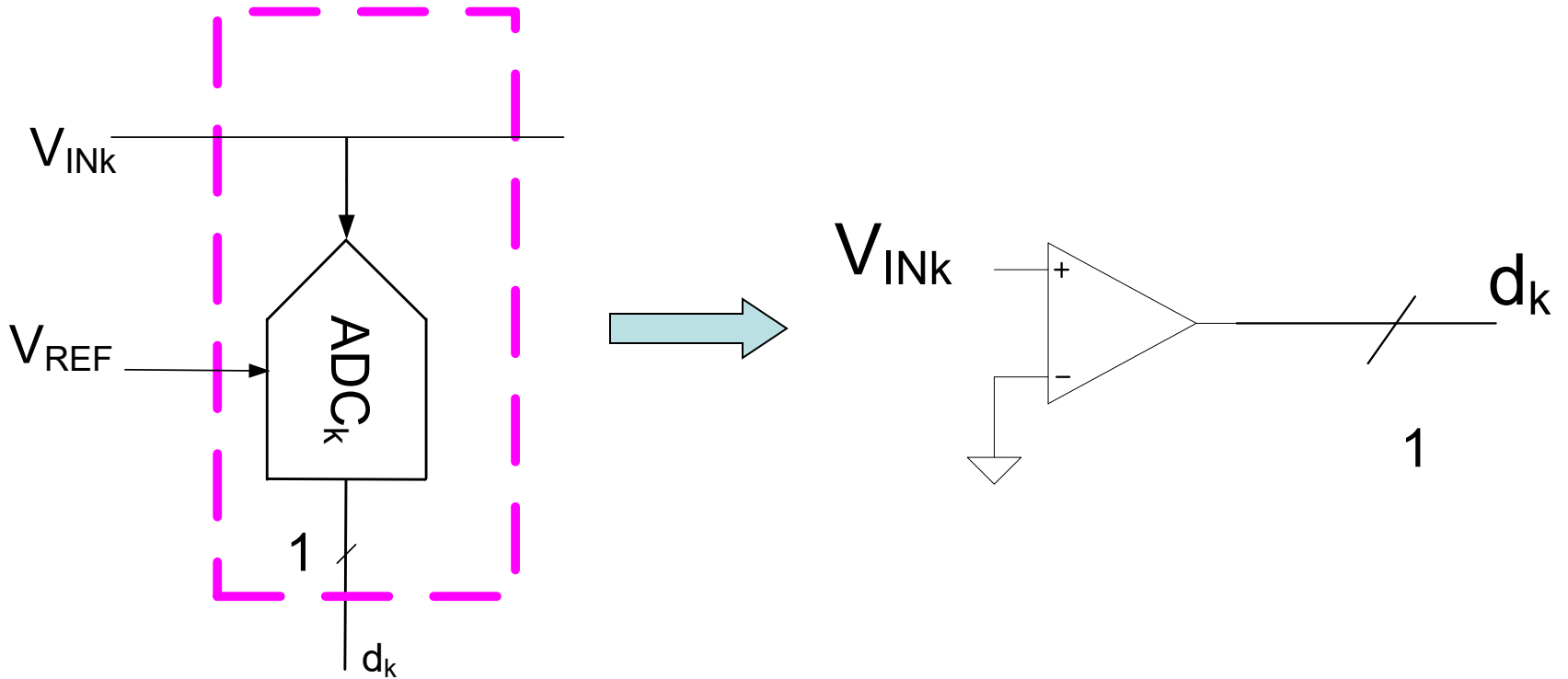
Usually Realized as  
Single SC Block

# 1-bit/Stage Pipeline Implementation



$$V_O = \begin{cases} 2V_{IN} + \frac{V_{REF}}{2} & V_{IN} < 0 \\ 2V_{IN} - \frac{V_{REF}}{2} & V_{IN} > 0 \end{cases}$$

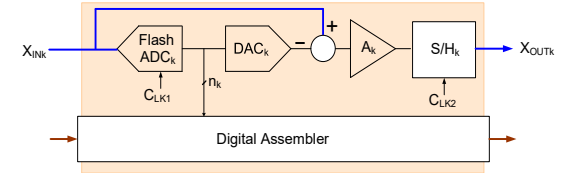
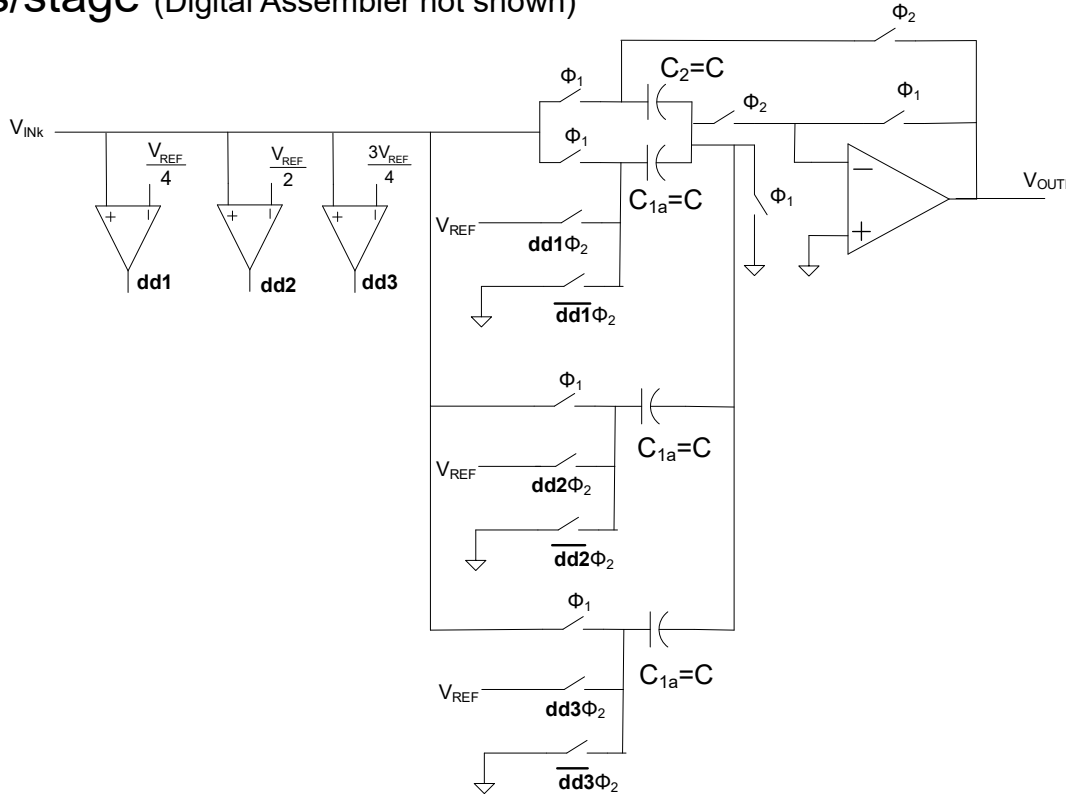
# 1-bit/Stage Pipeline Implementation



Review from Last Lecture

# Typical SC Pipeline Stage

For 2 bits/stage (Digital Assembler not shown)

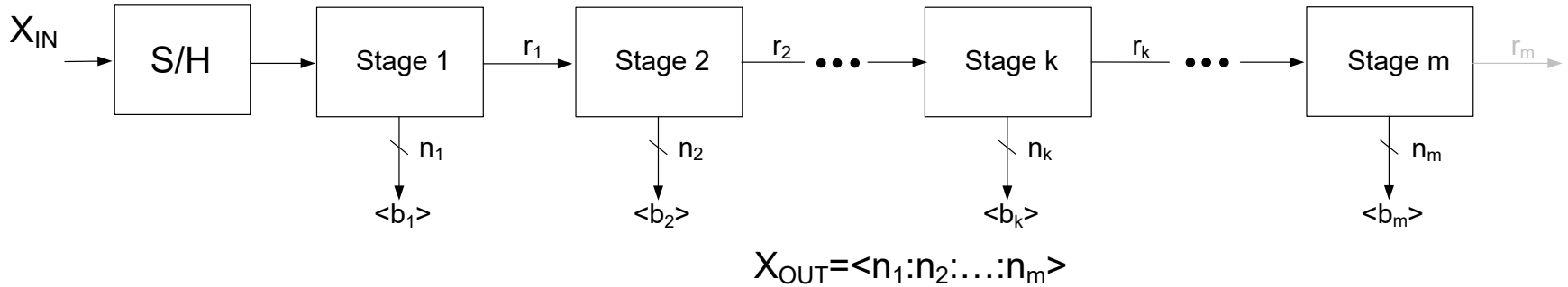


Gain = 4

$$V_{OUT} = V_{IN} \left( 1 + \frac{C_{1a} + C_{1b} + C_{1c}}{C_2} \right) - \left( d_{d1} \left( \frac{C_{1a}}{C_2} \right) + d_{d2} \left( \frac{C_{1b}}{C_2} \right) + d_{d3} \left( \frac{C_{1c}}{C_2} \right) \right) V_{REF} \longrightarrow V_{OUTk} = 4 V_{INk} - (d_{dd1} + d_{dd2} + d_{dd3}) V_{REF}$$

- Directly use thermometer code outputs
- Can be extended to more bits/stage
- Accurate gain possible with good layout

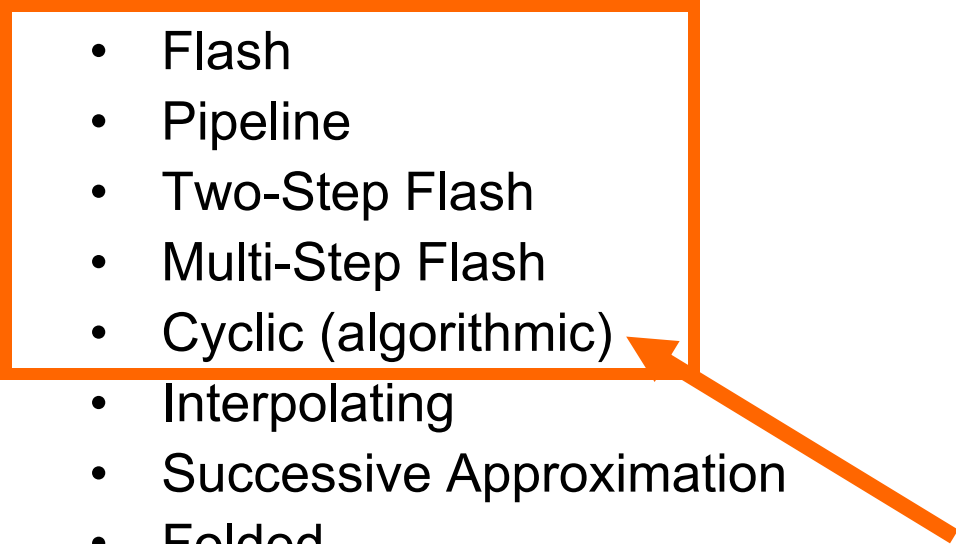
# Pipelined ADC



- Pipelined structure is widely used
- More than one bit/stage is often used
- Optimal number of bits/stage still an area of debate
- Conceptually can simply design one stage and then copy/paste to increase resolution
- Accuracy (and correspondingly power) in latter stages can be dramatically reduced
- Most power consumed in op amps
- Power dominantly allocated to S/H and MSB stages

# ADC Types

## Nyquist Rate

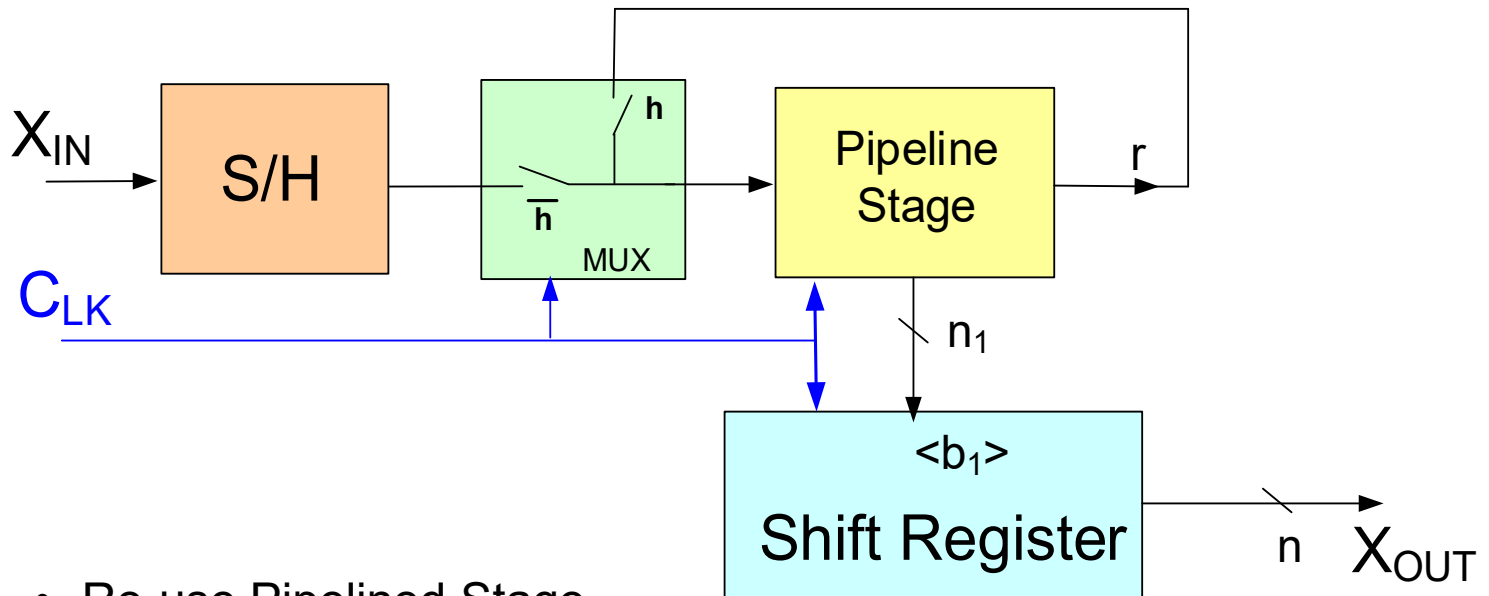
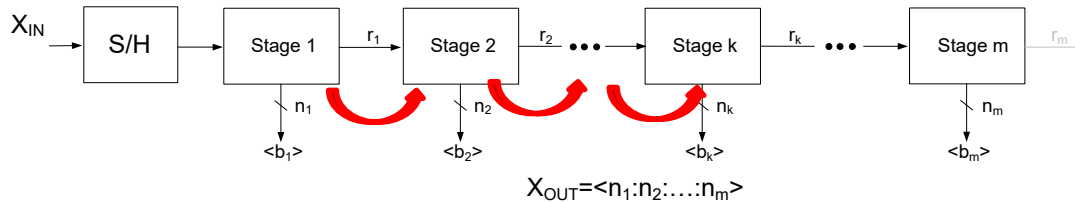
- Flash
  - Pipeline
  - Two-Step Flash
  - Multi-Step Flash
  - Cyclic (algorithmic)
  - Interpolating
  - Successive Approximation
  - Folded
  - Dual Slope
- 

## Over-Sampled

- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time



# Cyclic (Algorithmic) ADC



- Re-use Pipelined Stage
- Small amount of hardware
- Effective thru-put decreases

# ADC Types

## Nyquist Rate

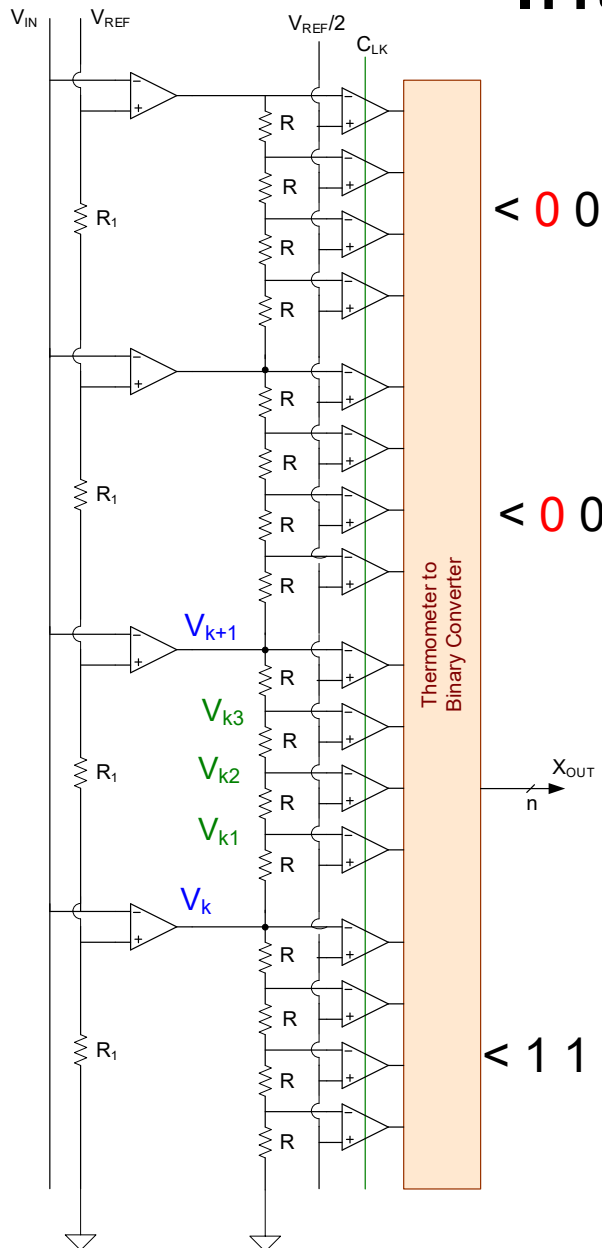
- Flash
- Pipeline
- Two-Step Flash
- Multi-Step Flash
- Cyclic (algorithmic)
- Interpolating
- Successive Approximation
- Folded
- Dual Slope

## Over-Sampled

- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time



# Interpolating ADC

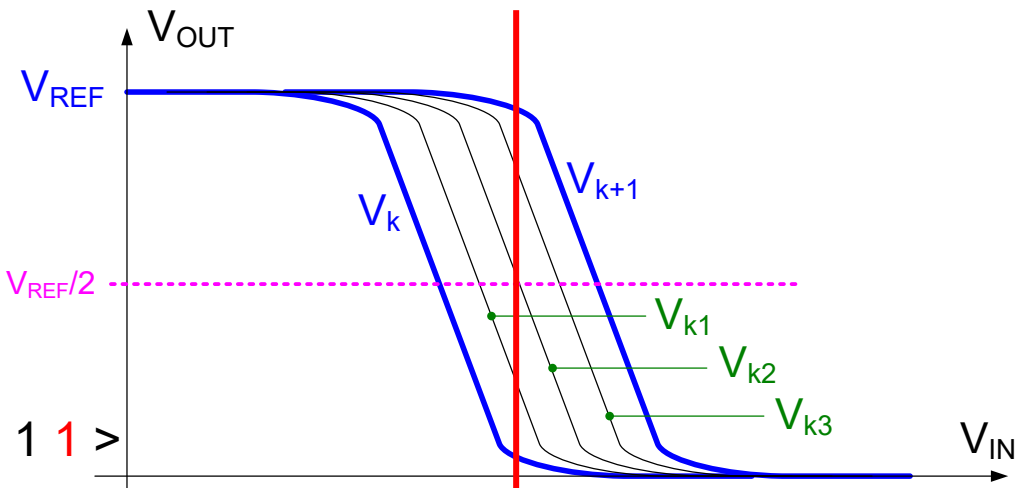


< 0 0 0 0 0 >

- Amplifiers are finite-gain saturating
- Amplifiers need not be accurate or linear
- Shown for 4-bit
- Same common-mode input on comparators

< 0 0 0 0 0 >

- Clocked comparators usually regenerative
- Reduces Offset Requirements for Comparators



< 1 1 1 1 1 >

< 1 1 0 0 0 >

Colored bits are shared

# ADC Types

## Nyquist Rate

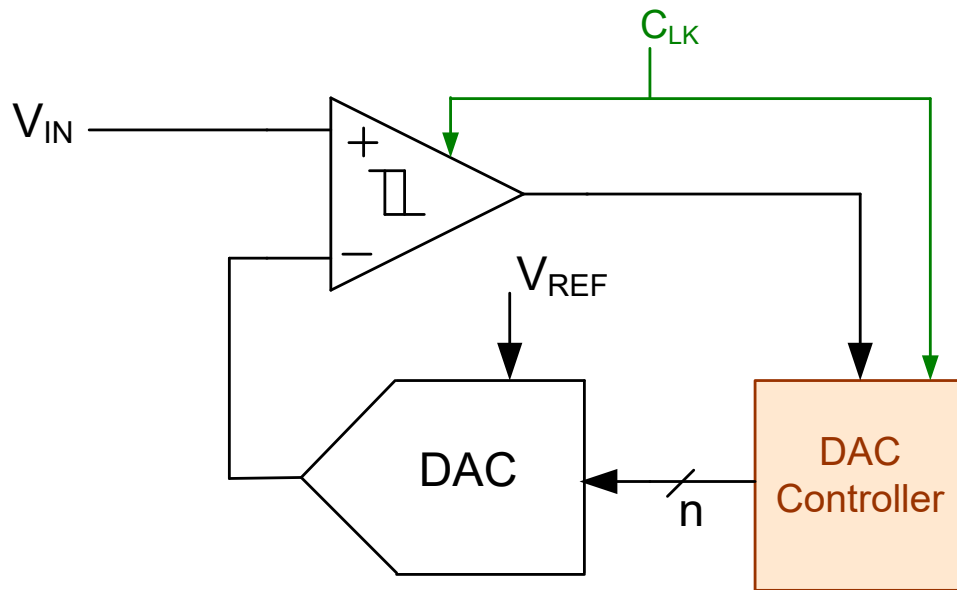
- Flash
- Pipeline
- Two-Step Flash
- Multi-Step Flash
- Cyclic (algorithmic)
- Interpolating
- Successive Approximation
- Folded
- Dual Slope

## Over-Sampled

- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time



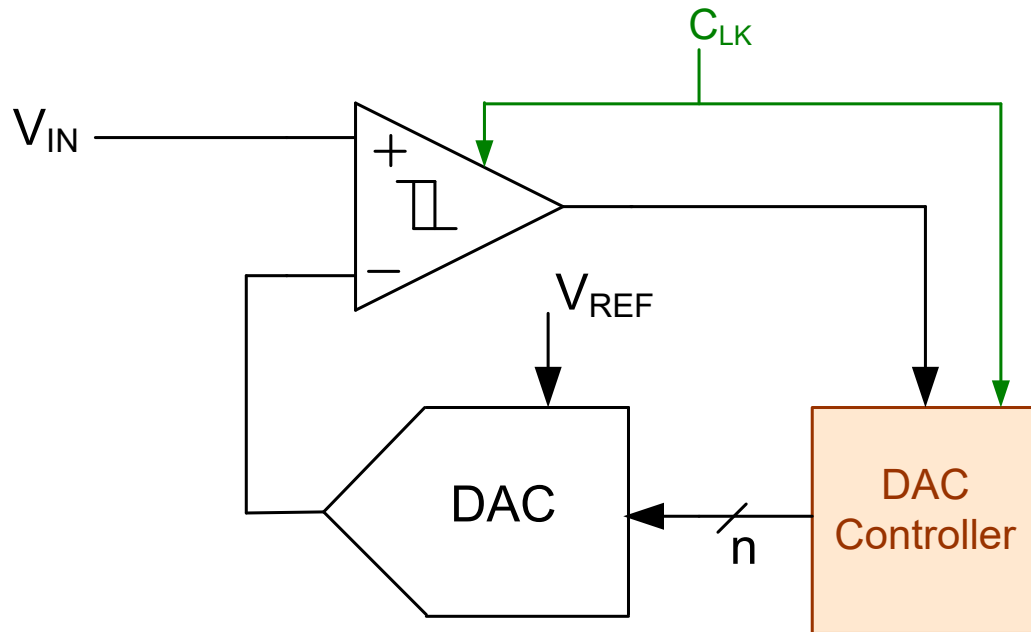
# SAR ADC



## ADCs Texas Instruments

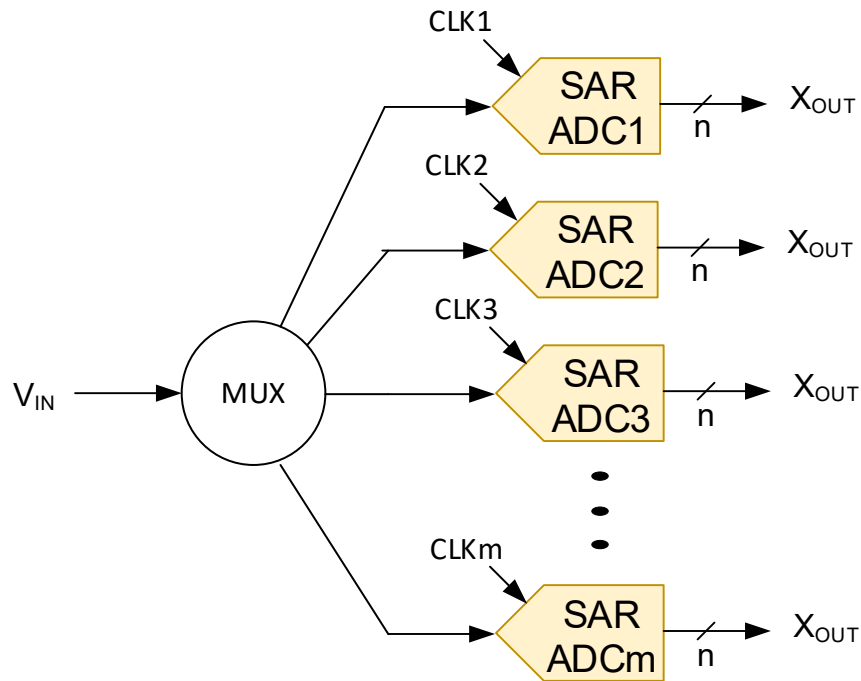
SAR		728
Pipeline		294
Delta Sigma		187
Folding Interpolating		66
Delta Sigma		
Modulator		9
Two-Step		6
Flash		3
Total		1293

# SAR ADC

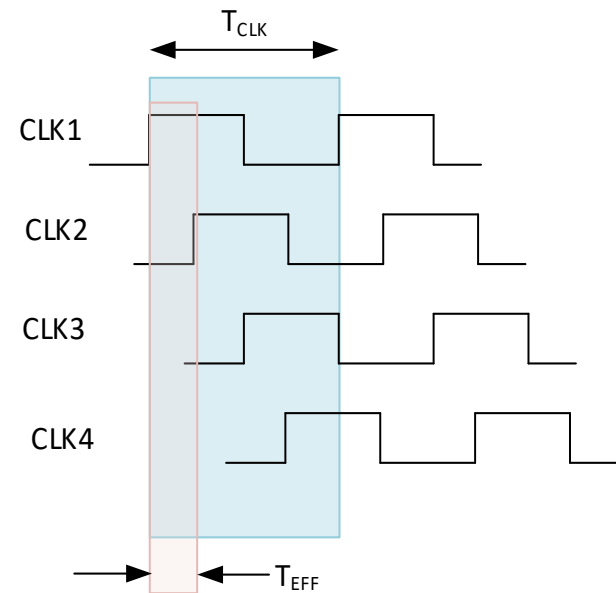


- DAC Controller may be simply U/D counter
- Binary search controlled by Finite State Machine is faster
- SAR ADC will have no missing codes if DAC is monotone
- Not very fast but can be small
- Any DAC can be used
- Single comparator !

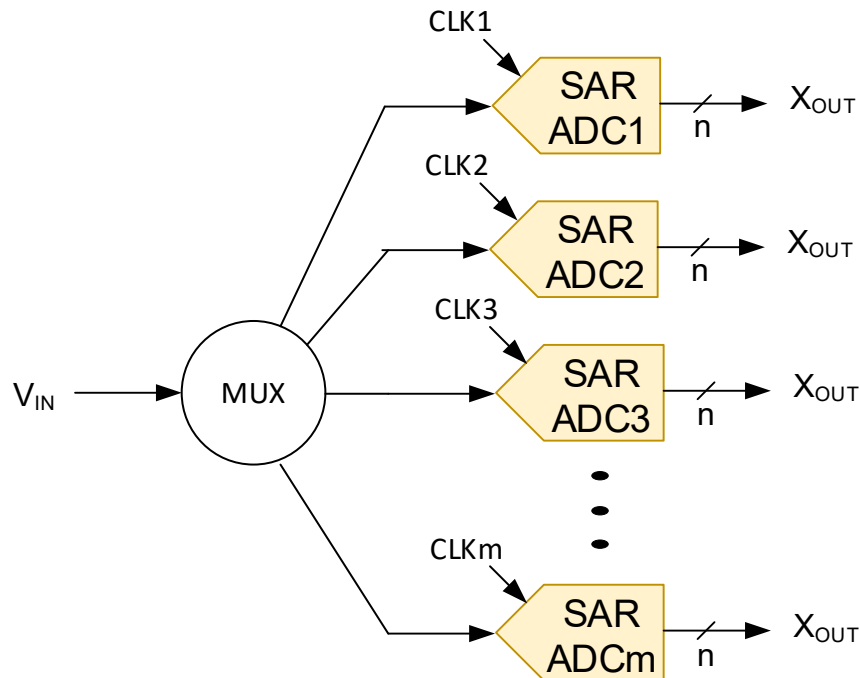
# Time Interleaved SAR ADC



Time interleaving increases effective conversion rate by factor of  $m$



# Time Interleaved SAR ADC



- Provides high-speed solution when single SAR can not operate fast enough
- May be more energy efficient even if single SAR can work
- May provide better performance than pipelined structure
- Matching between stages is critical
- Clock phasing is critical
- Idea is 40+ years old but only recently has become popular
- Calibration is essential to provide matching and phasing



# ADC Types

## Nyquist Rate

- Flash
- Pipeline
- Two-Step Flash
- Multi-Step Flash
- Cyclic (algorithmic)
- Interpolating
- Successive Approximation
- Folded
- Dual Slope

## Over-Sampled

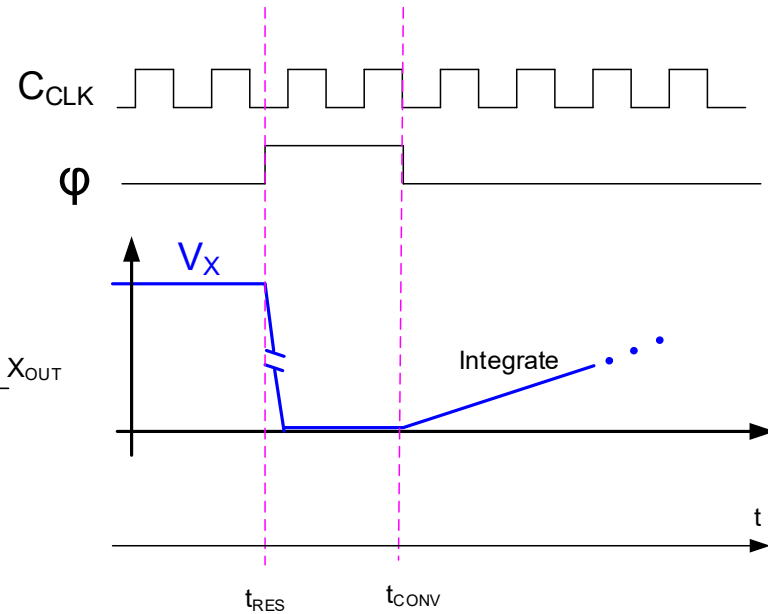
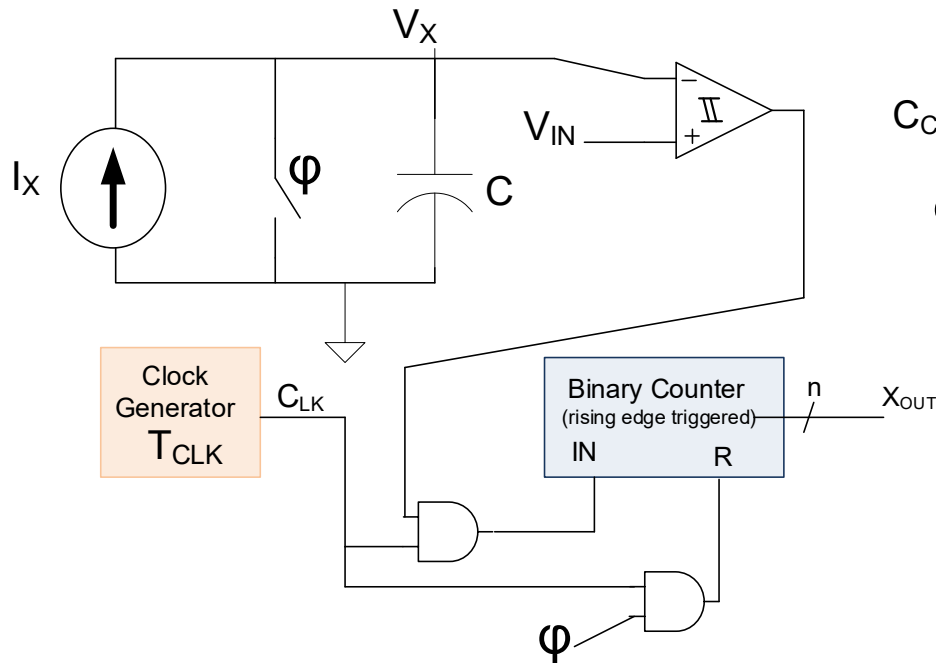
- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time

And Single Slope



# Single-Slope ADC

Sometimes Termed Integrating ADC



- Falling edge of  $\phi$  synchronous with respect to falling edge of  $C_{CLK}$
- Can convert asynchronously wrt  $C_{CLK}$  or can be a clocked ADC where conversion clock signal is synchronous wrt  $C_{CLK}$ .
- Output valid when comparator output goes low
- Note  $V_{REF}$  not explicitly shown in ADC architecture
- Very simple structure if  $C$  is off-chip

# Single-Slope ADC

Operation:

Assume  $V_X(t_{\text{CONV}})=0$

$$V_X(t) = \frac{1}{C} \int_{t_{\text{CONV}}}^t I_X dt = \frac{I_X}{C} (t - t_{\text{CONV}}) \quad (1)$$

Assume  $I_X, V_{\text{REF}}, R, C, T_{\text{CLK}}$  are selected to satisfy the relationship

$$V_{\text{REF}} = \frac{1}{C} \int_{t_{\text{CONV}}}^{t_{\text{CONV}} + 2^n T_{\text{CLK}}} I_X dt = \frac{I_X}{C} 2^n T_{\text{CLK}} \quad \text{thus} \quad V_{\text{LSB}} = \frac{V_{\text{REF}}}{2^n} = \frac{I_X}{C} T_{\text{CLK}} \quad (2)$$

Comparator will stop counter when  $V_X = V_{\text{IN}}$  and counter output will be  $X_{\text{OUT}} = k$

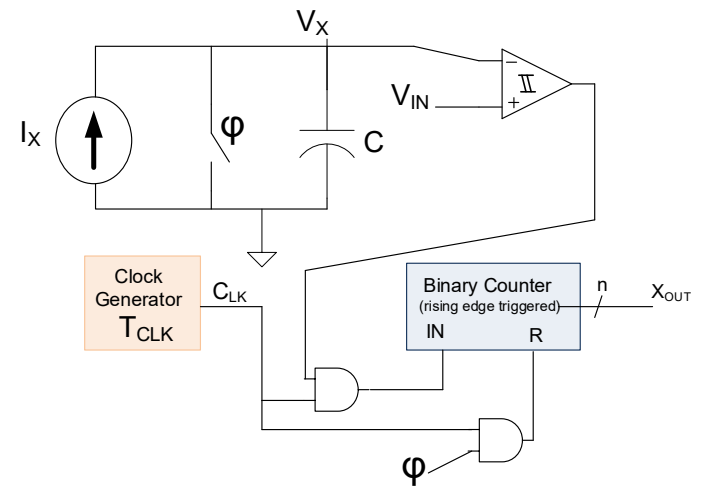
$$\text{thus } V_X(t_{\text{CONV}} + kT_{\text{CLK}}) = V_{\text{IN}} + \varepsilon \quad \text{where } 0 < \varepsilon < V_{\text{LSB}}$$

It follows from (1) that

$$V_X(t_{\text{CONV}} + kT_{\text{CLK}}) = \frac{I_X}{C} kT_{\text{CLK}} = V_{\text{IN}} + \varepsilon \quad (3)$$

And finally from (2) and (3) that

$$V_{\text{IN}} = k \left( \frac{I_X}{C} T_{\text{CLK}} \right) - \varepsilon \cong \frac{k}{2^n} V_{\text{REF}}$$

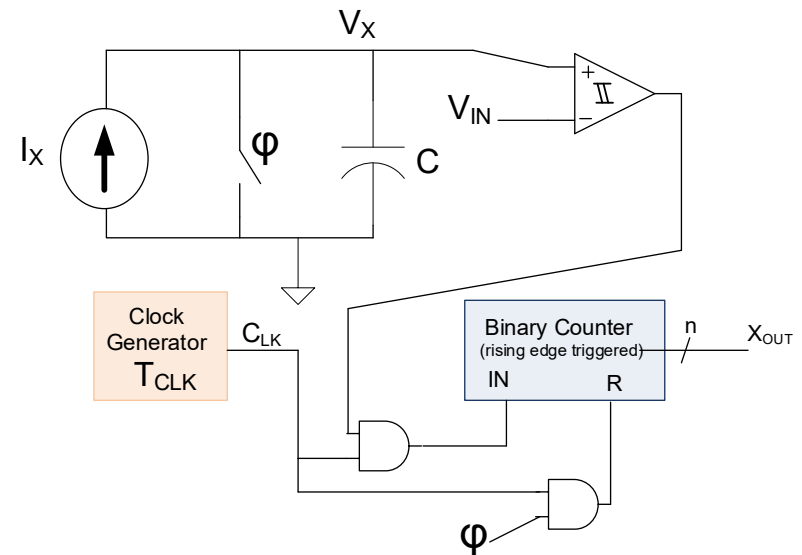


# Single-Slope ADC

$I_X, V_{REF}, R, C, T_{CLK}$  must satisfy the relationship

$$V_{REF} = \frac{I_X}{C} 2^n T_{CLK} \quad (1)$$

$$V_{IN} \cong \frac{k}{2^n} V_{REF}$$



Benefits: Very simple structure and can provide a low-cost easy solution for low speed applications

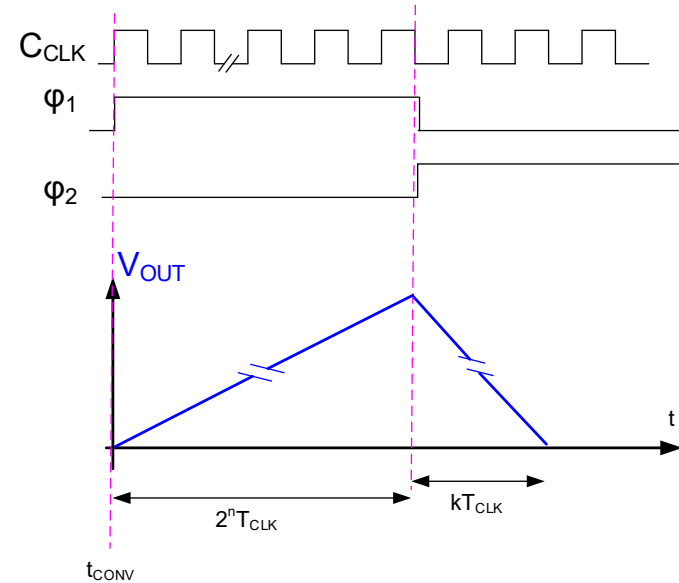
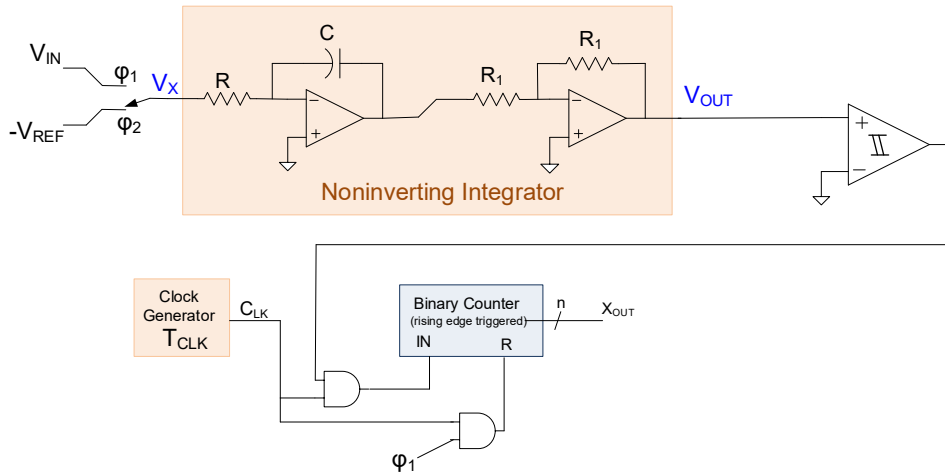
Limitations:

- Process variations make it difficult to satisfy (1)
- $C$  is usually large and thus off chip is often most practical
- Linearity of  $C$  important (since often off-chip)
- Nonlinearity in  $I_X$  degrades performance
- $R_{OUT}$  of  $I_X$  degrades performance
- Slow
- Not widely used

Options for improving performance:

- Introduce self-calibration cycle to satisfy (1) by trimming  $I_X$  or  $C$
- Use high-impedance current source
- Use OP-Amp Based RC integrator

# Dual-Slope ADC



- Output valid when comparator output transitions to Low
- Must set RC time constants and  $T_{CLK}$  so output does not saturate
- Shown as noninverting integrator but slight modification will also work with inverting integrator
- Other integrator structures could be used
- Can leave one or more clock cycles between integrate up and integrate down

# Dual-Slope ADC

Operation:

$$V_{OUT}(t) = \frac{1}{RC} \int_{t_{CONV}}^t V_X dt$$

During  $\phi_1$ , integrate  $V_{IN}$  for time  $2^n T_{CLK}$

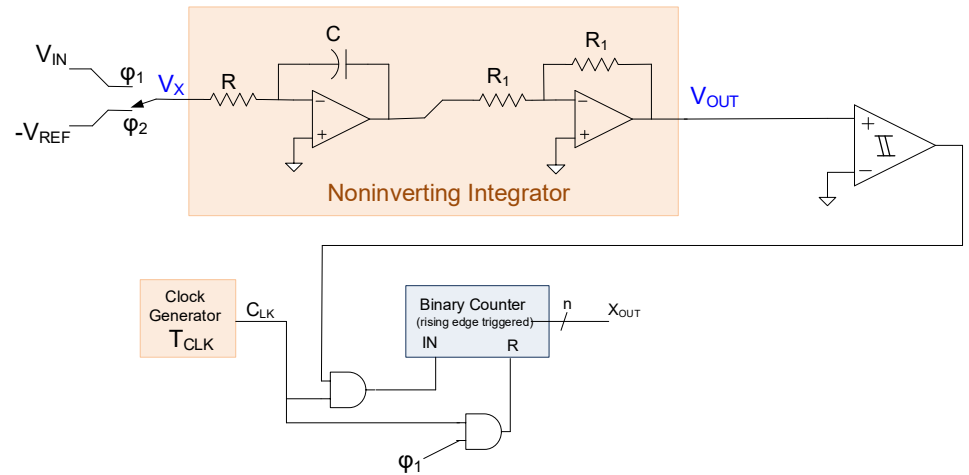
At end of integrate up interval,  $V_{OUT}(2^n T_{CLK}) = \frac{1}{RC} V_{IN} 2^n T_{CLK}$

Reset counter at time  $2^n T_{CLK}$

During  $\phi_2$ , integrate  $-V_{REF}$  until comparator goes low and count clock transitions during down integration interval. At time comparator changes states,  $V_{OUT}=0$  and code in counter is  $k$

$$0 = \frac{1}{RC} \int_{t_{CONV}}^{t_{CONV} + 2^n T_{CLK}} V_{IN} dt - \frac{1}{RC} \int_{t_{CONV} + 2^n T_{CLK}}^{t_{CONV} + 2^n T_{CLK} + k T_{CLK}} V_{REF} dt \quad \Rightarrow \quad \frac{1}{RC} V_{IN} 2^n T_{CLK} = \frac{1}{RC} V_{REF} k T_{CLK}$$

Solving, obtain:  $V_{IN} = \frac{k}{2^n} V_{REF}$



# Dual-Slope ADC

$$V_{IN} = \frac{k}{2^n} V_{REF}$$

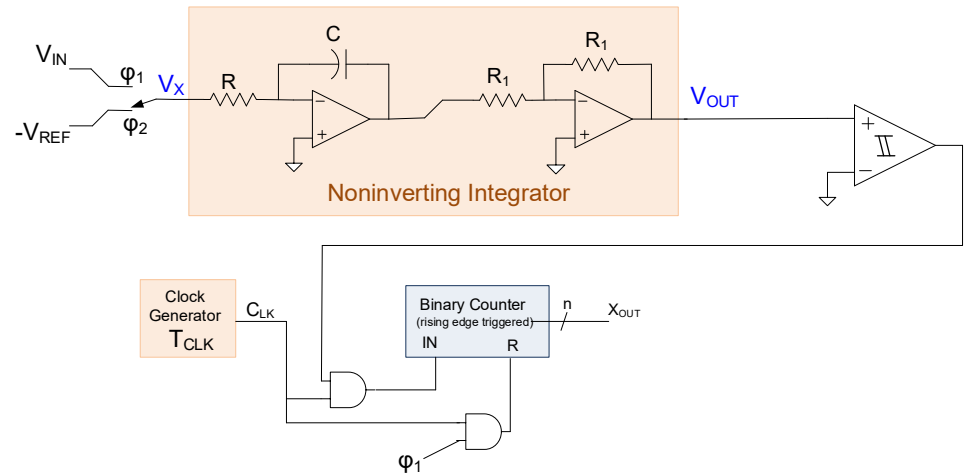
Observations:

Benefits

- Not dependent upon R, C, or  $T_{CLK}$  (provided integrator does not saturate)
- Very simple structure that can give good results and cost can be low
- Inherently monotone

Limitations:

- Capacitor large and likely must be off-chip
- Linearity of capacitor is important (particularly of concern when off-chip)
- Slow
- Not widely used





Stay Safe and Stay Healthy !



End of Lecture 37